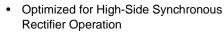


## N-Channel 30-V (D-S) MOSFET

PRODU	CT SUMMARY		
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)
30	0.008 at V <sub>GS</sub> = 10 V	13	6.1 nC
30	0.011 at V <sub>GS</sub> = 4.5 V	11	0.1110

#### **FEATURES**

- · Halogen-free
- TrenchFET® Power MOSFET

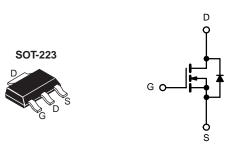




100 % UIS Tested



- Notebook CPU Core
  - High-Side Switch



N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b>	<b>5</b> T <sub>A</sub> = 25 °C, unles	s otherwise noted	d		
Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		$V_{DS}$	30	V	
Gate-Source Voltage		$V_{GS}$	± 20	v	
	T <sub>C</sub> = 25 °C		13		
Continuous Drain Current (T <sub>.1</sub> = 150 °C)	T <sub>C</sub> = 70 °C	I-	10		
Continuous Diam Current (1) = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	9 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C		7 <sup>b, c</sup>	^	
Pulsed Drain Current		I <sub>DM</sub>	45	A	
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	I.	3.7		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	2.0 <sup>b, c</sup>		
Single Pulse Avalanche Current		I <sub>AS</sub>	20		
Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	21	mJ	
	T <sub>C</sub> = 25 °C		4.1		
Maximum Power Dissipation	T <sub>C</sub> = 70 °C	P <sub>D</sub>	2.5	W	
	T <sub>A</sub> = 25 °C		2.2 <sup>b, c</sup>	VV	
	T <sub>A</sub> = 70 °C		1.3 <sup>b, c</sup>		
Operating Junction and Storage Temperature Ra	ange	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 s	R <sub>thJA</sub>	39	55	°C/W
Maximum Junction-to-Foot (Drain)	Steady State	R <sub>thJF</sub>	25	29	C/VV

#### Notes

- a. Base on  $T_C$  = 25 °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under Steady State conditions is 85 °C/W.

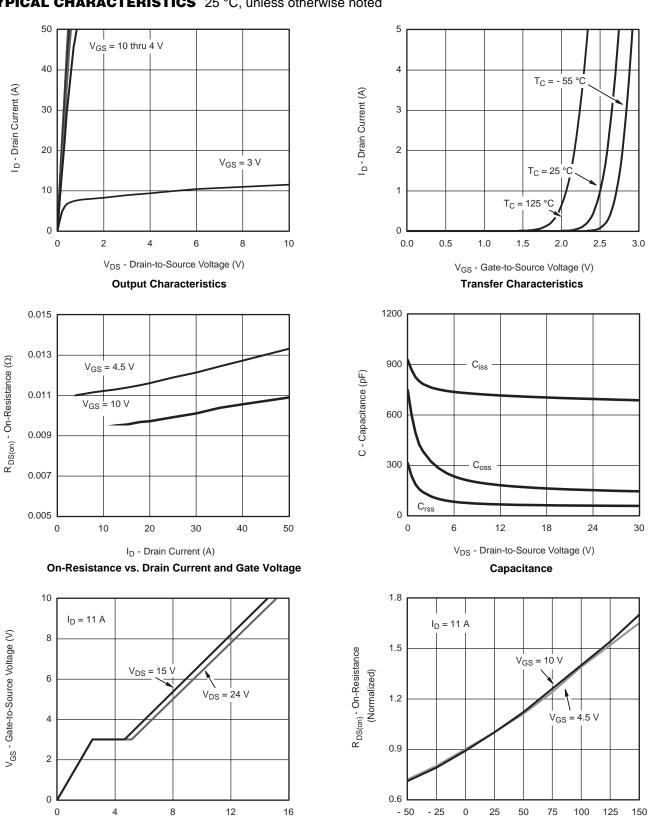


Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 250A		26		14/00
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = 250 μA		- 6		mV/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	0.8		2.5	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current		V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V			1	μA
	IDSS	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			10	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	20			Α
	_	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10 A		0.008		Ω
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 9 A		0.011		
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 10 A		50		S
Dynamic <sup>b</sup>	<u> </u>				I	
Input Capacitance	C <sub>iss</sub>			800		
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V, f = 1 MHz		165		pF
Reverse Transfer Capacitance	C <sub>rss</sub>			73		
Total Gate Charge		V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10 A		15	23	nC
	Q <sub>g</sub>			6.8	10.2	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = 15 \text{ V}, V_{GS} = 5 \text{ V}, I_{D} = 10 \text{ A}$		2.5		
Gate-Drain Charge	Q <sub>gd</sub>			2.3		
Gate Resistance	R <sub>g</sub>	f = 1 MHz	0.36	1.8	3.6	Ω
Turn-On Delay Time	t <sub>d(on)</sub>			16	23	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, $R_L$ = 1.4 $\Omega$		12	16	1
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 9 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		16	22	
Fall Time	t <sub>f</sub>			10	18	
Turn-On Delay Time	t <sub>d(on)</sub>			8	16	- ns
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, $R_L$ = 1.4 $\Omega$		10	20	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 9 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		16	22	
Fall Time	t <sub>f</sub>			8	15	
Drain-Source Body Diode Characterist	tics					
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			10	٨
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				50	A
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = 9 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			15	30	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = 9 A, dI/dt = 100 A/μs, T <sub>J</sub> = 25 °C		6	12	nC
Reverse Recovery Fall Time	t <sub>a</sub>	$i_F = 9 \text{ A}$ , $u_i/u_i = 100 \text{ A/µs}$ , $i_J = 25 \text{ C}$		8		
Reverse Recovery Rise Time	t <sub>b</sub>	7		7		ns

- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$  b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.





服务热线:400-655-8788

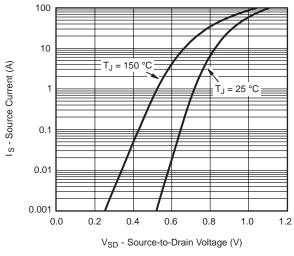
Q<sub>q</sub> - Total Gate Charge (nC)

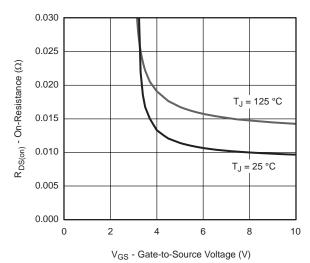
**Gate Charge** 

T<sub>J</sub> - Junction Temperature (°C)

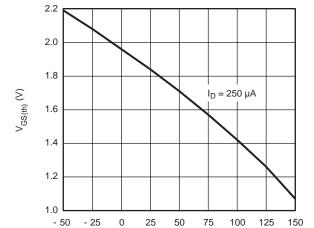
On-Resistance vs. Junction Temperature



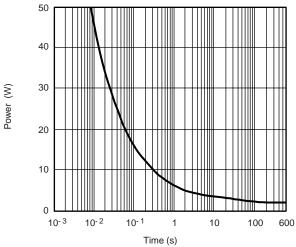




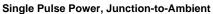
#### Source-Drain Diode Forward Voltage

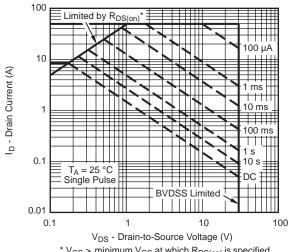


On-Resistance vs. Gate-to-Source Voltage



#### T<sub>J</sub> - Temperature (°C) **Threshold Voltage**

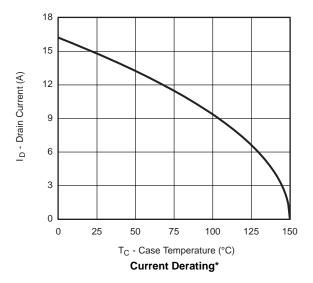


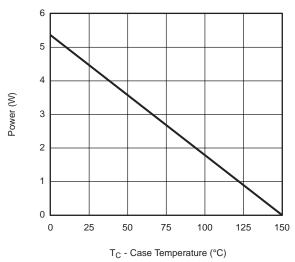


\*  $V_{GS} > \mbox{minimum } V_{GS}$  at which  $R_{DS(on)}$  is specified

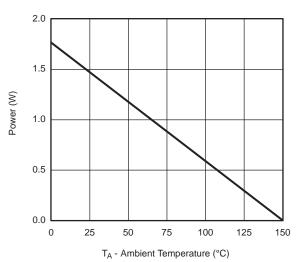
Safe Operating Area, Junction-to-Ambient







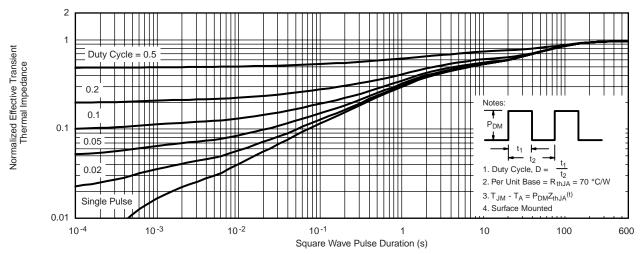
Power Derating, Junction-to-Foot



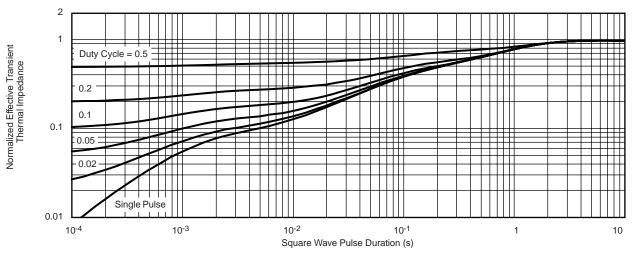
Power Derating, Junction-to-Ambient

\* The power dissipation  $P_D$  is based on  $T_{J(max)}$  = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





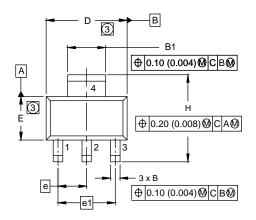
#### Normalized Thermal Transient Impedance, Junction-to-Ambient

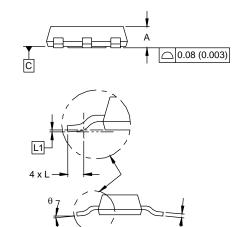


Normalized Thermal Transient Impedance, Junction-to-Foot



### SOT-223





DIM.	MILLIN	MILLIMETERS		HES
	MIN.	MAX.	MIN.	MAX.
А	1.55	1.80	0.061	0.071
В	0.65	0.85	0.026	0.033
B1	2.95	3.15	0.116	0.124
С	0.25	0.35	0.010	0.014
D	6.30	6.70	0.248	0.264
E	3.30	3.70	0.130	0.146
е	2.30 BSC		0.090	5 BSC
e1	4.60 BSC		0.181	BSC
Н	6.71	7.29	0.264	0.287
L	0.91	-	0.036	-
L1	0.061 BSC		0.0024	4 BSC
θ	-	10'	-	10'

ECN: S-82109-Rev. A, 15-Sep-08

DWG: 5969

#### Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimensions are shown in millimeters (inches).
- 3. Dimension do not include mold flash.
- 4. Outline conforms to JEDEC outline TO-261AA.

服务热线:400-655-8788

7



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